# **General Description**

The 83052I-01 is a 2-bit, 2:1, Single-ended Multiplexer and a member of the family of High Performance Clock Solutions from IDT. The 83052I-01 has two selectable single-ended clock inputs and two single-ended clock outputs. The output has a  $V_{\text{DDO}}$  pin which may be set at 3.3V, 2.5V, or 1.8V, making the device ideal for use in voltage translation applications. An output enable pin places the output in a high impedance state which may be useful for testing or debug. Possible applications include systems with up to two transceivers which need to be independently set for different rates. For example, a board may have two transceivers, each of which need to be independently configured for 1 Gigabit Ethernet or 1 Gigabit Fibre Channel rates. Another possible application may require the ports to be independently set for FEC (Forward Error Correction) or non-FEC rates. The device operates up to 250MHz and is packaged in a 16 TSSOP.

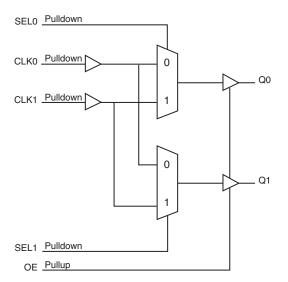
### Features

- 2-bit, 2:1 single-ended multiplexer
- Nominal output impedance:  $15\Omega (V_{DDO} = 3.3V)$
- Maximum output frequency: 250MHz
- Propagation delay: 3ns (maximum), V<sub>DD</sub> = V<sub>DDO</sub> = 3.3V
- Input skew: 85ps (maximum), V<sub>DD</sub> = V<sub>DDO</sub> = 3.3V
- Part-to-part skew: 500ps (maximum), V<sub>DD</sub> = V<sub>DDO</sub> = 3.3V
- Output skew: 65ps (maximum), V<sub>DD</sub> = V<sub>DDO</sub> = 3.3V
- Additive phase jitter, RMS (12KHz 20MHz): 0.15ps (typical)
- Operating supply modes:

V<sub>DD</sub>/V<sub>DDO</sub> 3.3V/3.3V 3.3V/2.5V 3.3V/1.8V 2.5V/2.5V 2.5V/1.8V

- -40°C to 85°C ambient operating temperature
- Available in lead-free (RoHS 6) package

## **Block Diagram**



### **Pin Assignment**

nc 🗖 1	16 🗌 nc
Vddo 🗌 2	15 🗖 VDDO
nc 🗖 3	14 🗖 nc
GND 🗖 4	<sup>13</sup> GND
Q1 🗖 5	12 🗖 Q0
SEL1 🗖 6	11 SEL0
CLK1 7	
	<sup>9</sup> □oe

83052I-01 16-Lead TSSOP

4.4mm x 5.0mm x 0.925mm package body G Package

# Table 1. Pin Descriptions

Number	Name	Туре		Description
1, 3, 14, 16	nc	Unused		No connect.
2, 15	V <sub>DDO</sub>	Power		Output supply pins.
4, 13	GND	Power		Power supply ground
5, 12	Q1, Q0	Output		Single-ended clock outputs. LVCMOS/LVTTL interface levels.
6, 11	SEL1, SEL0	Input	Pulldown	Clock select inputs. See Table 3, Control Input Function Table. LVCMOS / LVTTL interface levels.
7, 10	CLK1, CLK0	Input	Pulldown	Single-ended clock input. LVCMOS/LVTTL interface levels.
8	V <sub>DD</sub>	Power		Power supply pin.
9	OE	Input	Pullup	Output enable. When LOW, outputs are in HIGH impedance state. When HIGH, outputs are active. LVCMOS / LVTTL interface levels.

NOTE: Pullup and Pulldown refer to internal input resistors. See Table 2, Pin Characteristics, for typical values.

# **Table 2. Pin Characteristics**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
C <sub>IN</sub>	Input Capacitance			4		pF
R <sub>PULLUP</sub>	Input Pullup Resistor			51		kΩ
R <sub>PULLDOWN</sub>	Input Pulldown Resistor			51		kΩ
	Power Dissipation Capacitance (per output); NOTE 1	$V_{DDO} = 3.465V$		18		pF
C <sub>PD</sub>		$V_{DDO} = 2.625V$		19		pF
		$V_{DDO} = 2.0V$		19		pF
		$V_{DDO} = 3.465V$		15		Ω
R <sub>OUT</sub>	Output Impedance	$V_{DDO} = 2.625V$		17		Ω
		$V_{DDO} = 2.0 V$		25		Ω

## **Function Tables**

#### **Table 3. Control Input Function Table**

Control Inputs		Outputs		
SEL1 SEL0		Q0	Q1	
0	0	CLK0 (default)	CLK0	
0	1	CLK1	CLK0	
1	0	CLK0	CLK1	
1	1	CLK1	CLK1	

## **Absolute Maximum Ratings**

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics or AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V <sub>CC</sub>	4.6V
Inputs, V <sub>1</sub>	-0.5V to V <sub>DD</sub> + 0.5V
Outputs, V <sub>o</sub>	-0.5V to V <sub>DDO</sub> + 0.5V
Package Thermal Impedance, $\theta_{JA}$	100.3°C/W (0 mps)
Storage Temperature, T <sub>STG</sub>	-65°C to 150°C

### **DC Electrical Characteristics**

Table 4A. Power Supply DC Characteristics,  $V_{DD}$  = 3.3V ± 5%,  $V_{DDO}$  = 3.3V ± 5% or 2.5V ± 5% or 1.8V ± 0.2V,  $T_A$  = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
$V_{\text{DD}}$	Positive Supply Voltage		3.135	3.3	3.465	V
		3.135	3.3	3.465	V	
$V_{\text{DDO}}$	Output Supply Voltage		2.375	2.5	2.625	V
			1.6	1.8	2.0	V
I <sub>DD</sub>	Power Supply Current				40	mA
I <sub>DDO</sub>	Output Supply Current	No Load			5	mA

Table 4B. Power Supply DC Characteristics	$V_{DD} = 2.5V \pm 5\%, V_{DDO} =$	= $2.5V \pm 5\%$ or $1.8V \pm 0.2V$ , $T_A = -40^{\circ}C$ to $85^{\circ}C$
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Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>DD</sub>	Positive Supply Voltage		2.375	2.5	2.625	V
V			2.375	2.5	2.625	V
V <sub>DDO</sub> Output Supply Voltage		1.6	1.8	2.0	V	
I <sub>DD</sub>	Power Supply Current				40	mA
I <sub>DDO</sub>	Output Supply Current	No Load			5	mA

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
V	Innut Lligh Volt		$V_{DD} = 3.465V$	2		V <sub>DD</sub> + 0.3	V
V <sub>IH</sub>	Input High Volta	age	$V_{DD} = 2.625V$	1.7		V <sub>DD</sub> + 0.3	V
V	Input Low Volto	200	$V_{DD} = 3.465V$	-0.3		1.3	V
VIL	Input Low Volta	ige	$V_{DD} = 2.625V$	-0.3		0.7	V
1	CLK0, CLK1, SEL0, SEL1		$V_{DD} = V_{IN} = 3.465V \text{ or}$ 2.625V			150	μA
	High Current OE	$V_{DD} = V_{IN} = 3.465 V \text{ or}$ 2.625 V			5	μA	
	Input Low Current	CLK0, CLK1, SEL0, SEL1	$V_{DD} = 3.465V \text{ or } 2.625V,$ $V_{IN} = 0V$	-5			μA
IIL		OE	$V_{DD} = 3.465V \text{ or } 2.625V,$ $V_{IN} = 0V$	-150			μA
			$V_{\text{DDO}} = 3.3V \pm 5\%$	2.6			V
V <sub>OH</sub>	Output High Vo	ltage; NOTE 1	$V_{\text{DDO}} = 2.5V \pm 5\%$	1.8			V
			$V_{\text{DDO}} = 1.8V \pm 0.2V$	V <sub>DDO</sub> - 0.3			V
			$V_{\text{DDO}} = 3.3 \text{V} \pm 5\%$			0.5	V
V <sub>OL</sub>	Output Low Vol	Itage; NOTE 1	$V_{\text{DDO}} = 2.5V \pm 5\%$			0.45	V
			$V_{DDO} = 1.8V \pm 0.2V$	-5		0.35	V

#### **Table 4C. LVCMOS/LVTTL DC Characteristics,** $T_A = -40^{\circ}C$ to $85^{\circ}C$

NOTE 1: Outputs terminated with 50 $\Omega$  to V<sub>DDO</sub>/2. See Parameter Measurement Information, *Output Load Test Circuit diagrams.* 

### **AC Electrical Characteristics**

Table 5A. AC Characteristics,  $V_{\text{DD}}$  =  $V_{\text{DDO}}$  = 3.3V  $\pm$  5%,  $T_{\text{A}}$  =-40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f <sub>MAX</sub>	Output Frequency				250	MHz
tp <sub>LH</sub>	Propagation Delay, Low to High; NOTE 1		2.0	2.45	3.0	ns
tp <sub>HL</sub>	Propagation Delay, High to Low; NOTE 1		2.0	2.45	3.0	ns
<i>t</i> sk(i)	Input Skew; NOTE 2			20	85	ps
<i>t</i> sk(o)	Output Skew; NOTE 2, 3			15	65	ps
<i>t</i> sk(pp)	Part-to-Part Skew; NOTE 2, 4				500	ps
<i>t</i> jit	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter section, NOTE 5	Integration Range: 12kHz - 20MHz		0.15		ps
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fall Time	20% to 80%	200		600	ps
odc	Output Duty Cycle		40		60	%
MUXISOL	MUX Isolation	Unselected CLK input @100MHz		45		dB

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions

NOTE 1: Measured from the  $V_{DD}/2$  of the input to  $V_{DDO}/2$  of the output.

NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at V<sub>DDO</sub>/2.

NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltage and with equal load conditions. Using the same input on each device, the output is measured at  $V_{DDO}/2$ .

NOTE 5: Driving only one input clock.

#### Table 5B. AC Characteristics, $V_{\text{DD}}$ = 3.3V ± 5%, $V_{\text{DDO}}$ = 2.5V ± 5%, $T_{\text{A}}$ =-40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f <sub>MAX</sub>	Output Frequency				250	MHz
tp <sub>LH</sub>	Propagation Delay, Low to High; NOTE 1		2.2	2.55	3.0	ns
tp <sub>HL</sub>	Propagation Delay, High to Low; NOTE 1		2.2	2.55	3.0	ns
<i>t</i> sk(i)	Input Skew; NOTE 2			10	50	ps
<i>t</i> sk(o)	Output Skew; NOTE 2, 3			20	70	ps
<i>t</i> sk(pp)	Part-to-Part Skew; NOTE 2, 4				500	ps
<i>t</i> jit	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter section, NOTE 5	Integration Range: 12kHz - 20MHz		0.12		ps
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fall Time	20% to 80%	200		600	ps
odc	Output Duty Cycle		40		60	%
MUXISOL	MUX Isolation	Unselected CLK input @100MHz		45		dB

NOTE: See Notes above.

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
f <sub>MAX</sub>	Output Frequency				250	MHz
tp <sub>LH</sub>	Propagation Delay, Low to High; NOTE 1		2.2	3.1	4.0	ns
tp <sub>нL</sub>	Propagation Delay, High to Low; NOTE 1		2.2	3.1	4.0	ns
<i>t</i> sk(i)	Input Skew; NOTE 2			15	60	ps
<i>t</i> sk(o)	Output Skew; NOTE 2, 3			30	100	ps
<i>t</i> sk(pp)	Part-to-Part Skew; NOTE 2, 4				500	ps
<i>t</i> jit	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter section, NOTE 5	Integration Range: 12kHz - 20MHz		0.14		ps
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fall Time	20% to 80%	150		1000	ps
odc	Output Duty Cycle	f <sub>out</sub> < 200MHz	40		60	%
MUXISOL	MUX Isolation	Unselected CLK input @100MHz		45		dB

#### Table 5C. AC Characteristics, $V_{DD}$ = 3.3V ± 5%, $V_{DDO}$ = 1.8V ± 0.2V, $T_A$ =-40°C to 85°C

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions

NOTE 1: Measured from the  $V_{DD}/2$  of the input to  $V_{DDO}/2$  of the output.

NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at V<sub>DDO</sub>/2.

NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltage and with equal load conditions. Using the same input on each device, the output is measured at  $V_{DDO}/2$ .

NOTE 5: Driving only one input clock.

#### Table 5D. AC Characteristics, $V_{\text{DD}} = V_{\text{DDO}} = 2.5V \pm 5\%$ , $T_{\text{A}} = -40^{\circ}\text{C}$ to $85^{\circ}\text{C}$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units	
f <sub>MAX</sub>	Output Frequency				250	MHz	
tp <sub>LH</sub>	Propagation Delay, Low to High; NOTE 1		2.0	2.7	3.4	ns	
tp <sub>HL</sub>	Propagation Delay, High to Low; NOTE 1		2.0	2.7	3.4	ns	
<i>t</i> sk(i)	Input Skew; NOTE 2			15	55	ps	
<i>t</i> sk(o)	Output Skew; NOTE 2, 3			20	75	ps	
<i>t</i> sk(pp)	Part-to-Part Skew; NOTE 2, 4				500	ps	
<i>t</i> jit	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter section, NOTE 5	Integration Range: 12kHz - 20MHz		0.19		ps	
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fall Time	20% to 80%	200		600	ps	
odc	Output Duty Cycle		40		60	%	
MUXISOL	MUX Isolation	Unselected CLK input @100MHz		45		dB	

NOTE: See Notes above.

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum 250	Units MHz
f <sub>MAX</sub>	Output Frequency					
tp <sub>LH</sub>	Propagation Delay, Low to High; NOTE 1		2.0	3.1	4.2	ns
tp <sub>нL</sub>	Propagation Delay, High to Low; NOTE 1		2.0	3.1	4.2	ns
<i>t</i> sk(i)	Input Skew; NOTE 2			30	135	ps
<i>t</i> sk(o)	Output Skew; NOTE 2, 3			30	95	ps
<i>t</i> sk(pp)	Part-to-Part Skew; NOTE 2, 4				500	ps
<i>t</i> jit	Buffer Additive Phase Jitter, RMS; refer to Additive Phase Jitter section, NOTE 5	Integration Range: 12kHz - 20MHz		0.17		ps
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fall Time	20% to 80%	150		1000	ps
odc	Output Duty Cycle		40		60	%
MUXISOL	MUX Isolation	Unselected CLK input @100MHz		45		dB

#### Table 5E. AC Characteristics, $V_{DD}$ = 2.5V ± 5%, $V_{DDO}$ = 1.8V ± 0.2V, $T_A$ =-40°C to 85°C

NOTE: Electrical parameters are guaranteed over the specified ambient operating temperature range, which is established when the device is mounted in a test socket with maintained transverse airflow greater than 500 lfpm. The device will meet specifications after thermal equilibrium has been reached under these conditions

NOTE 1: Measured from the  $V_{DD}/2$  of the input to  $V_{DDO}/2$  of the output.

NOTE 2: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions. Measured at  $V_{\text{DDO}}/2$ .

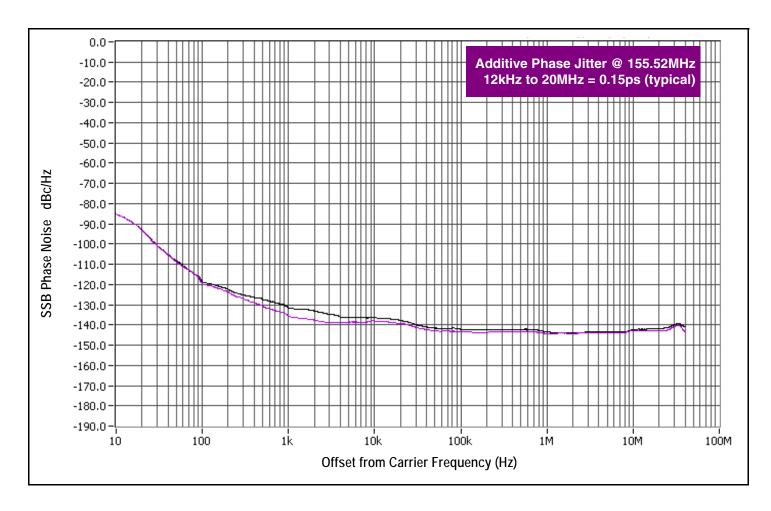
NOTE 4: Defined as skew between outputs on different devices operating at the same supply voltage and with equal load conditions. Using the same input on each device, the output is measured at  $V_{DDO}/2$ .

NOTE 5: Driving only one input clock.

## **Additive Phase Jitter**

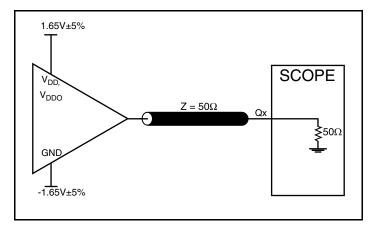
The spectral purity in a band at a specific offset from the fundamental compared to the power of the fundamental is called the *dBc Phase Noise*. This value is normally expressed using a Phase noise plot and is most often the specified plot in many applications. Phase noise is defined as the ratio of the noise power present in a 1Hz band at a specified offset from the fundamental frequency to the power value of the fundamental. This ratio is expressed in decibels (dBm) or a ratio of the power in the 1Hz band

to the power in the fundamental. When the required offset is specified, the phase noise is called a *dBc* value, which simply means dBm at a specified offset from the fundamental. By investigating jitter in the frequency domain, we get a better understanding of its effects on the desired application over the entire time record of the signal. It is mathematically possible to calculate an expected bit error rate given a phase noise plot.

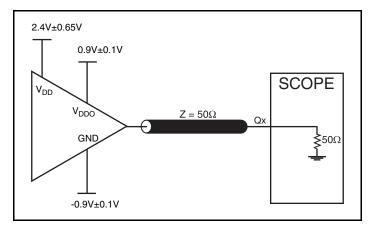


As with most timing specifications, phase noise measurements has issues relating to the limitations of the equipment. Often the noise floor of the equipment is higher than the noise floor of the device. This is illustrated above. The device meets the noise floor of what is shown, but can actually be lower. The phase noise is dependent on the input source and measurement equipment.

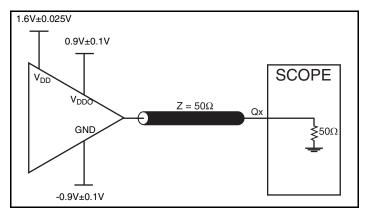
## **Parameter Measurement Information**



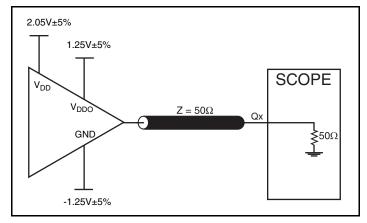
3.3V Core/3.3V LVCMOS Output Load AC Test Circuit



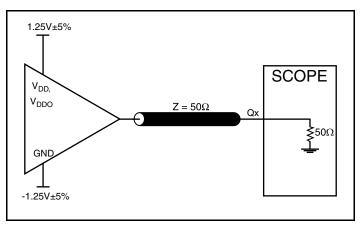
3.3V Core/ 1.8V LVCMOS Output Load AC Test Circuit



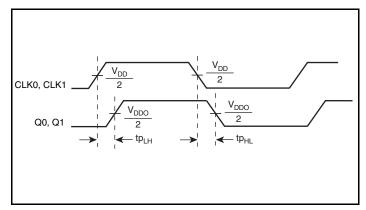
2.5V Core/ 1.8V LVCMOS Output Load AC Test Circuit



3.3V Core/2.5V LVCMOS Output Load AC Test Circuit

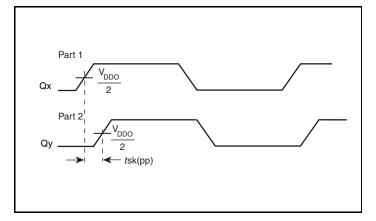


2.5V Core/ 2.5V LVCMOS Output Load AC Test Circuit

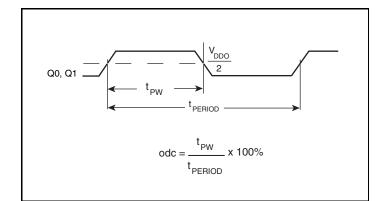




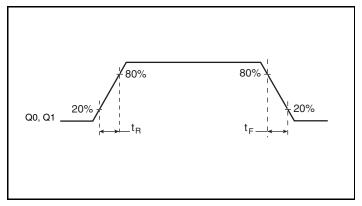
### Parameter Measurement Information, continued



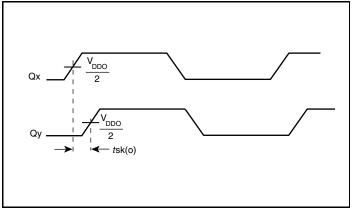
Part-to-Part Skew



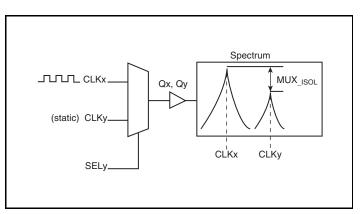
**Output Duty Cycle/Pulse Width/Period** 



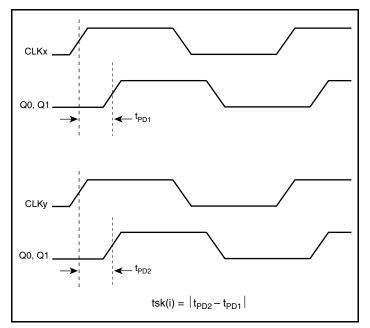
**Output Rise/Fall Time** 











#### Input Skew

# **Application Information**

### **Recommendations for Unused Input and Output Pins**

#### Inputs:

#### **LVCMOS Control Pins**

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A  $1k\Omega$  resistor can be used.

#### **CLK Inputs**

For applications not requiring the use of a clock input, it can be left floating. Though not required, but for additional protection, a  $1k\Omega$  resistor can be tied from the CLK input to ground.

#### Outputs:

#### LVCMOS Outputs

All unused LVCMOS output can be left floating. There should be no trace attached.

## **Reliability Information**

#### Table 6. $\theta_{\text{JA}}$ vs. Air Flow Table for a 16 Lead TSSOP

$\theta_{JA}$ vs. Air Flow					
Meters per Second	0	1	2.5		
Multi-Layer PCB, JEDEC Standard Test Boards	100.3°C/W	96.0°C/W	93.9°C/W		

NOTE: Most modern PCB design use multi-layered boards. The data in the second row pertains to most designs.

### **Transistor Count**

The transistor count for 83052I-01is: 967

# Package Outline and Package Dimensions

Package Outline - G Suffix for 16 Lead TSSOP

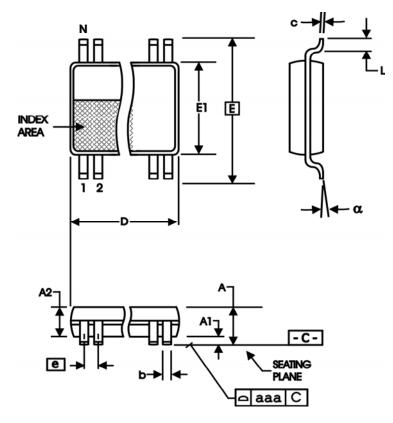


Table 7. Package Dimensions for 16 Lead TSSOP

All Dimensions in Millimeters					
Symbol	Minimum Maximum				
N	16				
Α		1.20			
A1	0.5 0.15				
A2	0.80 1.05				
b	0.19	0.30			
С	0.09	0.20			
D	4.90	5.10			
E	6.40 Basic				
E1	4.30	4.50			
е	0.65 Basic				
L	0.45	0.75			
α	0°	8°			
aaa	0.10				

Reference Document: JEDEC Publication 95, MO-153

# **Ordering Information**

#### Table 8. Ordering Information

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
83052AGI-01LF	052AI01L	"Lead-Free" 16 Lead TSSOP	Tube	-40°C to 85°C
83052AGI-01LFT	052AI01L	"Lead-Free" 16 Lead TSSOP	Tape & Reel	-40°C to 85°C

# **Revision History Sheet**

Rev	Table	Page	Description of Change	Date
А	Т3	2	Corrected Control Input Function Table.	
А	Т8	13	Ordering Information Table - deleted "ICS" prefix from Part/Order Number column.	3/9/09
А	Т8	13	Removed leaded orderable parts from Ordering Information table	11/14/12
		1	Features Section - removed reference to leaded packages.	
А		1	General Description - removed ICS Chip and HiPerClockS. Remove prefix of ICS on the part number.	12/16/15
	Т8	13	Removed LF note below the table. Updated header and footer.	



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